

## 4<sup>th</sup> International Symposium on Electronic Design, Test & Applications (DELTA 2008)



**Hong Kong, January 23-25, 2008**

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Hong Kong University of Science and Technology

The Hong Kong Electron Devices and Solid State Circuits (ED/SSC) Joint Chapter

**In co-operation with:** Celoxica Ltd, Solomon Systech Limited and Chinese University of Hong Kong.

DELTA 2008 is the 4<sup>th</sup> in a series of very successful workshops. Its mission is to bring together scientists, engineers and researchers from all over the world to meet and discuss cutting-edge research and latest results in the emerging areas of electronic design, fabrication, test, advanced system applications and related areas.

**Scope:** Original contributions are sought in the wide and multi-disciplinary areas of digital and analog electronics design, test and applications including (but not limited to):

### Design

- Digital and Analog Integrated Circuits and Systems
- System Architecture, Simulation and Modelling
- Microprocessors, ASICs and FPGAs
- Power Electronics and power management
- Devices and process
- MicroPhotonics, Opto-VLSI
- Multi-Chip and packaging technologies
- Emerging Technologies and sensors

### Applications

- Communications and Networking
- Signal and image Processing, DSP
- Fuzzy Logic and Neural Networks
- Instrumentation, Measurements and Control
- Medical Electronics and Biomedical devices
- Automotive, Security
- Real-Time and Embedded Systems
- Multimedia Systems and Applications

### Testing

- System Testing and Design Verification
- Built-In Self-test Techniques
- Design for Testability, Boundary Scan
- Analog and Mixed-Signal and RF Test
- Fault-Tolerance and Robustness
- Concurrent Checking and On-Line Testing
- Measurement for Reliability and Safety Assessment
- Characterisation Testing, Performance Modelling and Analysis
- Sequential Circuits Test and Memory Test

**Special sessions:** Proposals are sought for organising special sessions and tutorials/seminars on “hot topics” in design, test and applications. Among the sessions of interest are

- Devices and sensors technologies
- Advances in FPGA Based Design
- MicroPhotonics and OptoVLSI Design & Test
- Embedded Systems design and Test

**Submission of Papers:** Prospective authors are invited to submit:

- Full paper (4-6 pages) or an extended abstract (2-3 pages)
- Affiliation and address of each author
- The contact author’s postal and e-mail address

All submissions should be made electronically as PDF (preferred) or standard non-encapsulated Postscript files through the website <http://www.ece.ust.hk/delta2008>. In submitting an abstract the authors agree that, upon acceptance, they will prepare the final manuscript in time for the inclusion into the formal IEEE Computer Society published proceedings, and will present the paper at the Symposium. Final manuscripts will not be published without advance registration. Manuscripts will be peer-reviewed by the Program Committee.

### Key Dates:

Submission	<b>September 21, 2007</b>
Notification of Acceptance	<b>November 2, 2007</b>
Submission of final manuscripts	<b>November 16, 2007</b>

### Further information:

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